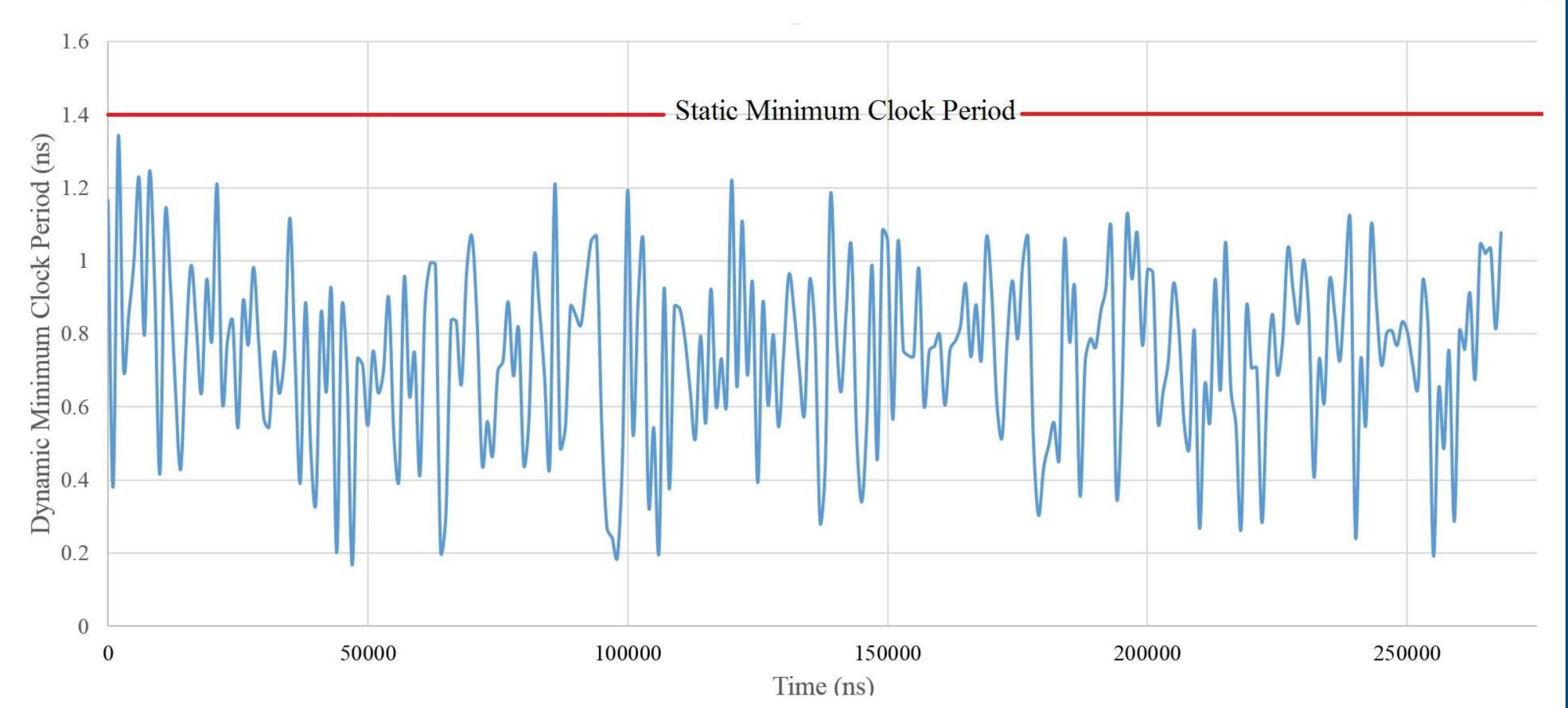
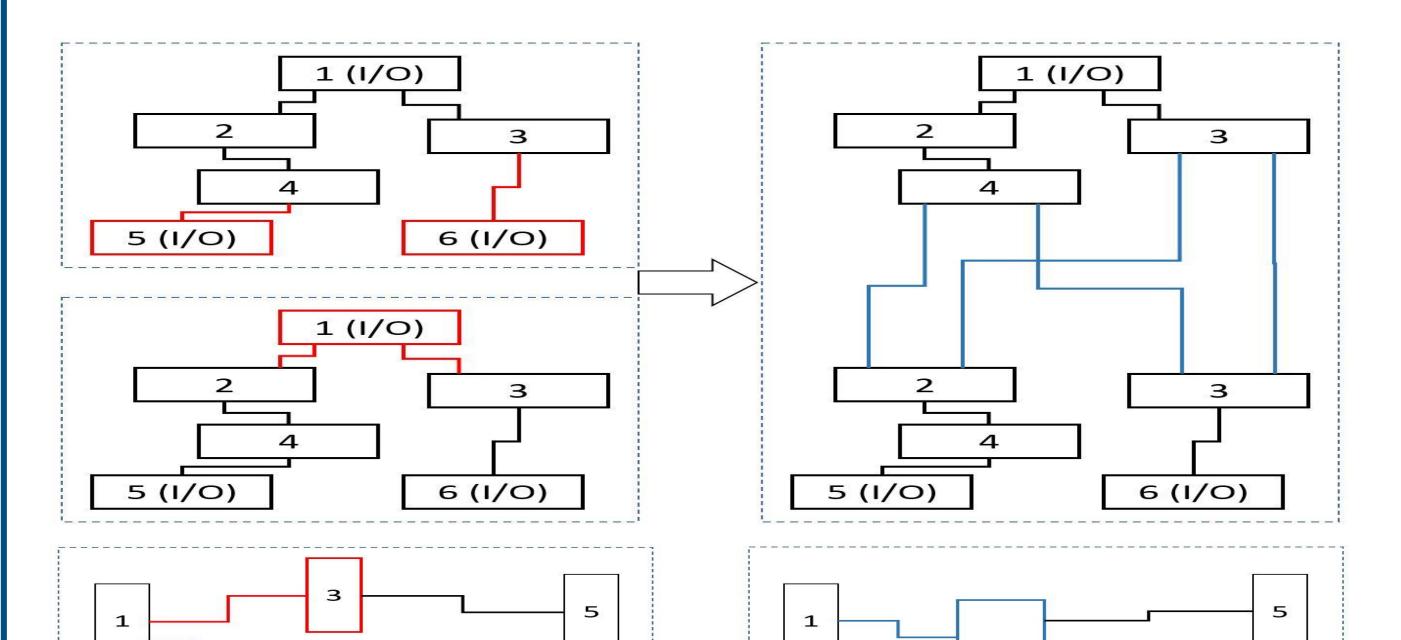
Clustered Timing Model: Statistical Modeling of Variability for Dynamic Estimation of Errors **Omid Assare and Rajesh Gupta** University of California, San Diego

Motivation

The behavior of CMOS circuits is increasingly susceptible to variations in the manufacturing process environmental conditions. The traditional and hardware-to-software model consisting of a set of

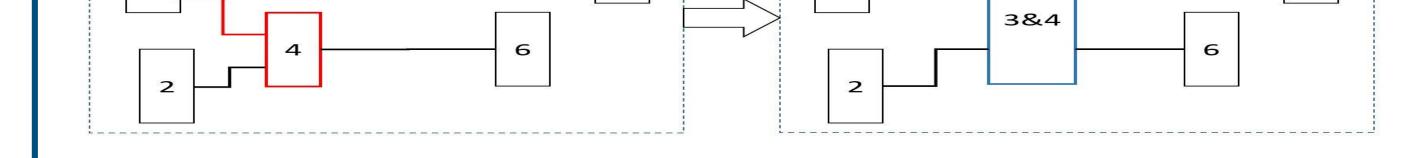


instructions with fixed and deterministic timing and functional behaviors is no longer sufficient. The new models need to dynamically predict the next state of the system based on the software it is running and the environmental conditions it is placed in, and be aware of the non-determinism due the physical variations.



Clustered Timing Model

The State of a sequential circuit consists of the contents of all its registers (including memory cells) and its primary I/O which together we call state storing elements. State Storing Element Clustering defines an equivalence relation on the state of the circuit, partitioning its state storing elements into a set of State Storing Clusters (SSCs) and the paths into hyperpaths. There is a hyperpath between two SSCs when there is at least one timing path connecting a state storing element output in the origin SSC to a state storing element input in the



destination SSC. Therefore, there can be zero, one, or two hyperpaths between two SSCs. The resulting model is called a **Clustered Timing Model (CTM)**.

ACTM for LEON3

ASIC Implementation

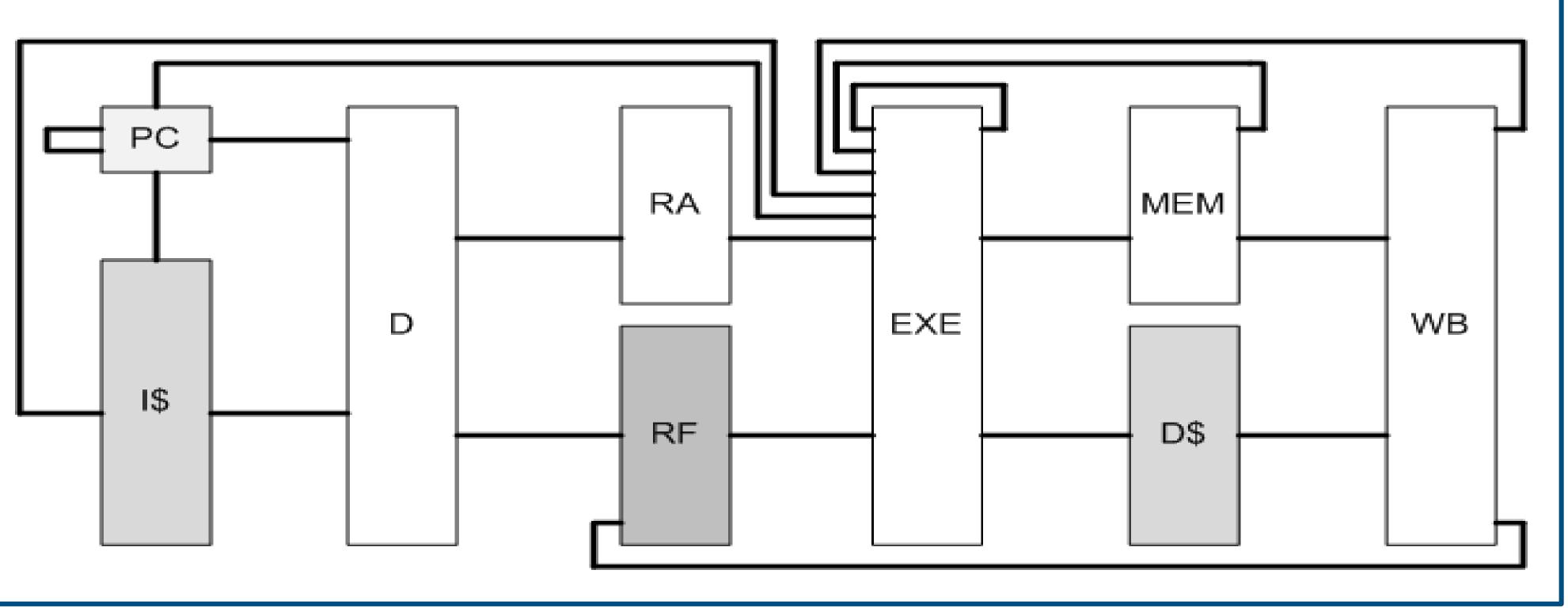
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One state storing clustering for LEON3 assigns an SSC to each pipeline stage register, an SSC to the PC, an SSC to the register file, and two SSCs to the caches, dividing the hyperpaths into four types:

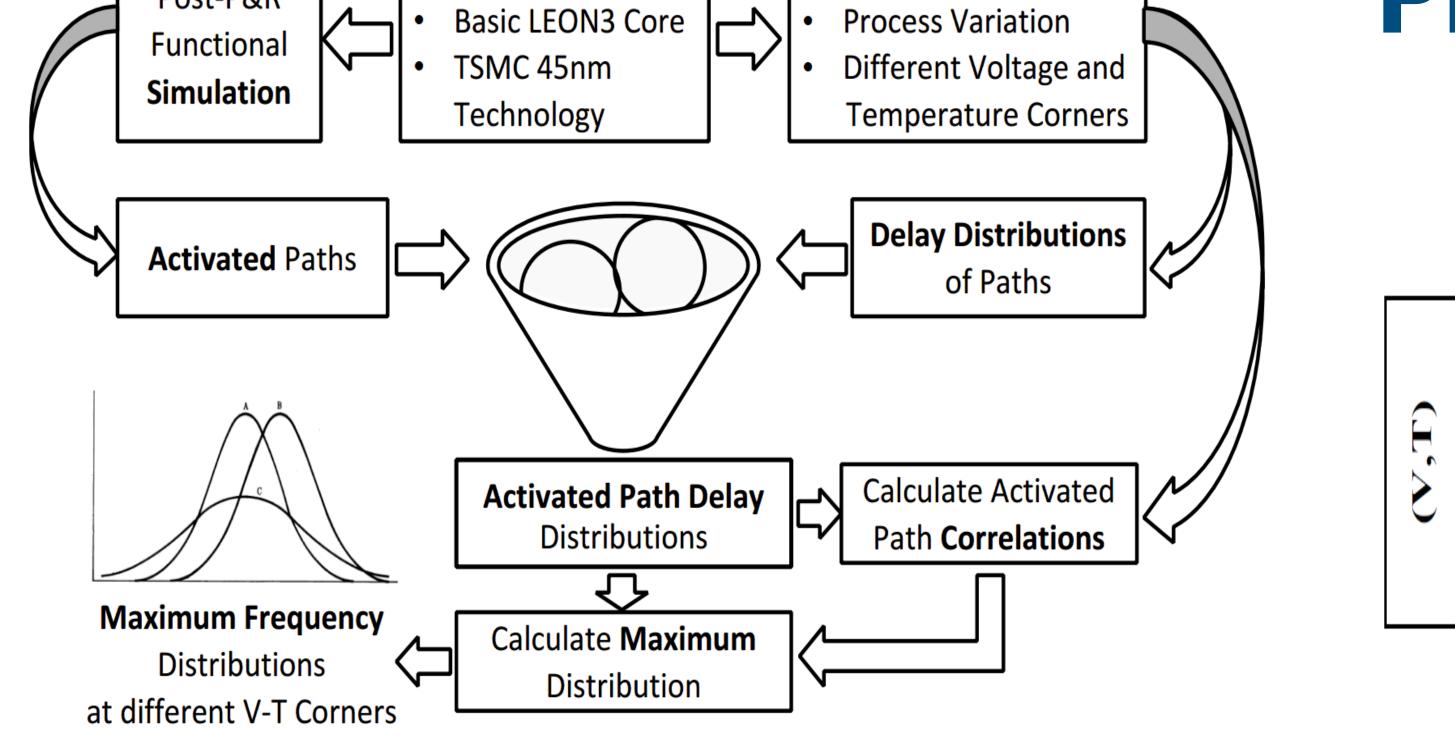
- I. Data Transfer hyperpaths
- II. Addition hyperpaths
- III. Logic hyperpaths

Post-P&R

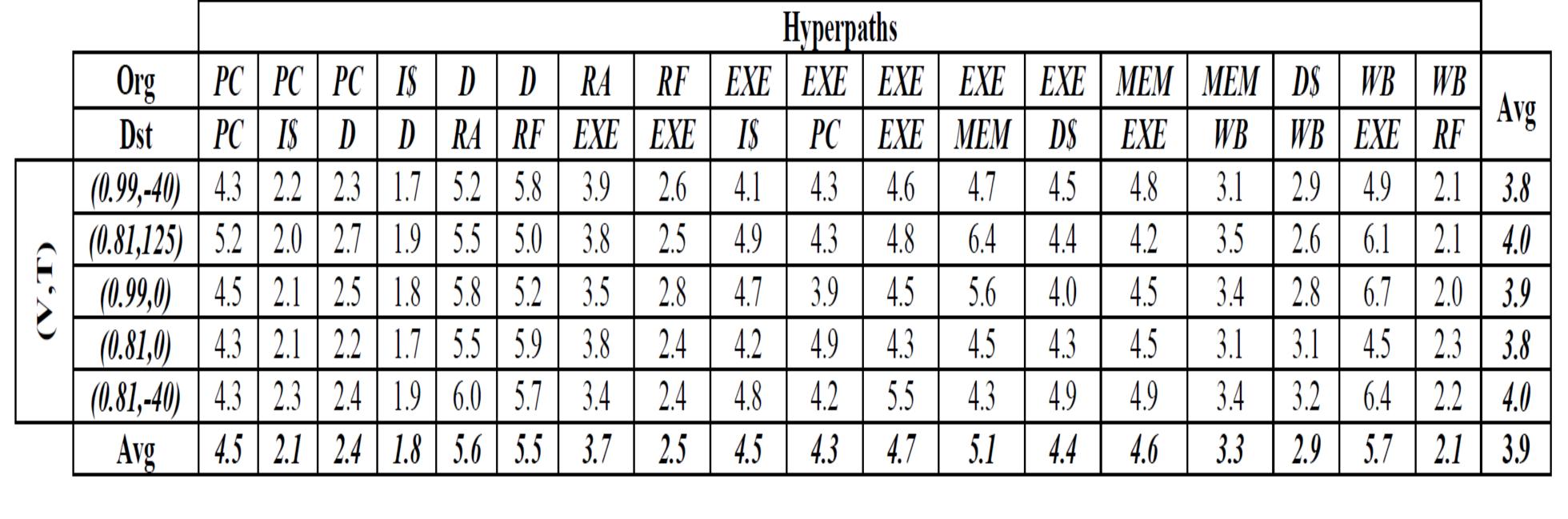
IV. Hybrid hyperpaths



Processor Characterization and Results



SSTA



NSF Expedition in Computing, Variability-Aware Software for Efficient Computing with Nanoscale Devices <u>http://variability.org</u>

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